

Notice of References Cited	Application/Control No. 10/644,264	Applicant(s)/Patent Under Reexamination BLUVSHTEYN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0031030 A1	02-2004	Kidder et al.	717/172
*	B	US-2003/0167354 A1	09-2003	Peppers et al.	709/327
*	C	US-4,558,413	12-1985	Schmidt et al.	707/203
*	D	US-6,751,794 B1	06-2004	McCaleb et al.	717/168
*	E	US-6,324,693 B1	11-2001	Brodersen et al.	717/177
*	F	US-6,976,251 B2	12-2005	Meyerson, Matthew S.	717/173
*	G	US-6,976,251 B2	12-2005	Meyerson, Matthew S.	717/173
*	H	US-6,895,513 B1	05-2005	Balasubramaniam et al.	726/24
*	I	US-6,950,863 B1	09-2005	Pham et al.	709/221
*	J	US-6,986,063 B2	01-2006	Colvin, David S.	705/51
*	K	US-6,282,709 B1	08-2001	Reha et al.	717/175
*	L	US-2003/0200207 A1	10-2003	Dickinson, Peter	707/3
*	M	US-5,752,042 A	05-1998	Cole et al.	717/173

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,151,708 A	11-2000	Pedrizetti et al.	717/173
*	B	US-5,845,077 A	12-1998	Fawcett, Philip E.	709/221
*	C	US-5,586,322 A	12-1996	Beck et al.	707/200
*	D	US-5,586,304 A	12-1996	Stupek et al.	717/170
*	E	US-5,528,490 A	06-1996	Hill, Charles E.	717/168
*	F	US-5,473,772 A	12-1995	Halliwell et al.	717/171
*	G	US-2002/0083053 A1	06-2002	Richard et al.	707/3
*	H	US-2001/0056425	12-2001	Richard, Bruno	707/10
*	I	US-6,078,912 A	06-2000	Buerger et al.	707/1
*	J	US-6,324,544 B1	11-2001	Alam et al.	707/201
*	K	US-2002/0059280 A1	05-2002	Slesinsky, Brian	707/100
*	L	US-2002/0065950 A1	05-2002	Katz et al.	709/318
*	M	US-2005/0033777 A1	02-2005	Moraes et al.	707/202

FOREIGN PATENT DOCUMENTS

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	N					
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	P					
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		10/644,264	Reexamination BLUVSHTEYN ET AL.
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*	A	US-6,751,794 B1	06-2004	McCaleb et al.	717/168
	B	US-			
	C	US-			
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